# AUTOMATED GUARDED BRIDGE FOR CALIBRATION OF MULTIMEGOHM STANDARD RESISTORS

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#### Abstract

The implementation of an automated guarded bridge for calibrating multimegohm standard resistors is described. A guarded Wheatstone bridge has been assembled with programmable dc calibrators in two of the arms allowing multiple ratios and test voltages to be remotely selected. Preliminary measurements are reported along with the balancing algorithm.

#### Introduction

Calibration of standard resistors from  $10~M\Omega$  to  $1~T\Omega$  at NIST are done manually on a guarded Wheatstone bridge or by using a semiautomated procedure with a teraohmmeter [1]. Both measurement systems require a degree of manual operation and have constraints that limit their flexibility. Neither system sufficiently covers the entire range of  $10~M\Omega$  to  $1~T\Omega$  with the lowest possible uncertainty. A single automated and robust system is being developed at NIST to replace the two aging systems, eliminate operator error, reduce uncertainties, and expand calibration services to resistances above  $1~T\Omega$ .

The method of using dc calibrators in two of the arms [2] is the approach selected to accomplish this task. The low impedance of the calibrators reduces errors caused by leakage currents. Guarding of the high side of the detector is also done to reduce leakages at that point. A graphical user interface (GUI) [3] has been written to provide flexibility to the measurement system and improved control of the instrumentation. Initial data indicate that the completed bridge should be able to calibrate multimegohm standard resistors at uncertainties of at least a factor of two below those presently assigned to calibrations of multimegohm resistors at NIST.

# Guarded Multimegohm Bridge

For a Wheatstone bridge [4], the equation at time of balance is

$$R_1/R_2 = R_X/R_D \tag{1}$$

where  $R_1$  and  $R_2$  are the ratio arms of the bridge and  $R_X$  and  $R_D$  are unknown and dummy resistors as shown in Figure 1. The detector D and voltage source V complete the traditional Wheatstone bridge.

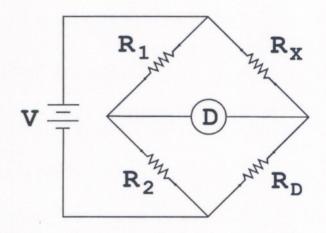


Fig. 1. Conventional Wheatstone Bridge.

In the automated multimegohm bridge, resistances  $R_1$  and  $R_2$  are replaced with programmable voltage sources  $V_1$  and  $V_2$  set to voltages  $E_1$  and  $E_2$  respectively yielding the following equation

$$E_1/E_2 = R_x/R_p \tag{2}$$

at time of balance. The bridge voltage supplied by source V shown in Figure 1 now is generated by  $V_{\rm 1}$  and  $V_{\rm 2}.$  Substituting programmable voltage sources for the main ratio arm and adding a guard resistor network to the bridge yields the circuit shown in Figure 2 where  $r_{\rm X}$  and  $r_{\rm D}$  are guard resistors.

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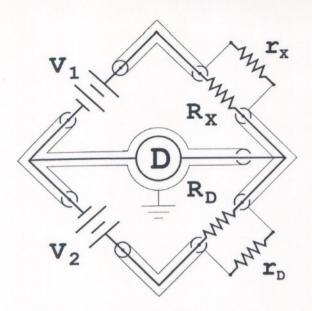


Fig. 2. Guarded Multimegohm Bridge.

### **Balancing Procedure**

An electrometer with a resolution of  $\pm 3$  fA in the current mode is used as the detector to measure the difference in the currents,  $\Delta I$ , flowing through  $R_X$  and  $R_D$ . Initially the voltage sources are set to  $E_{1\text{Est}}$  and  $E_2$ , the nominal ratio of  $R_X/R_D$ . The current  $\Delta I$  is measured by the detector. The estimated output  $E_{1\text{Est}}$  of source  $V_1$ , required to drive the bridge to a null, is calculated using the following equation

$$E_{1Est}' = [\Delta I + E_2 / R_D] R_X$$
 (3)

where  $R_D$  and  $R_X$  are nominal resistances. The source  $V_1$  is then set to the voltage  $E_{1\text{Est}}{}^{}$  which reduces  $\Delta I$  to a lower value  $\Delta I'$  bringing the bridge closer to a null. A linear fit is then applied to determine the exact setting of  $V_1$  required to reach a null based on the two iterations of  $E_{1\text{Est}}$  and  $\Delta I$  as shown in Equation 4 below

$$E_{1} = \left[ \Delta I \cdot E_{1Est}' - \Delta I' \cdot E_{1Est} \right] / \left[ \Delta I - \Delta I' \right]. \tag{4}$$

The unknown  $R_x$  can then be solved for by substituting  $E_1$ ,  $E_2$ , and  $R_D$  into Equation 2.

A GUI has been written that makes selection of voltage ranges and bridge ratio automatic. Balancing and computations are also controlled by the GUI along with the electrometer and calibrators.

The GUI allows the operator to easily select test parameters such as nominal resistances, test voltages, and bridge ratios. The event driven control structure of the GUI allows the software to respond immediately to changing parameters and handle errors without complex error handling routines. Changes in bridge parameters can be made without the risk of creating overload conditions such as a test voltage out of the calibrator range or applying voltages that could damage bridge components.

Other features of the GUI are multiple control options, linking to databases, plotting of data, and a user friendly interface.

### Results

Using the substitution method, agreement between the automated multimegohm system and the two existing measurement systems used at NIST has been well within uncertainties presently assigned by NIST to standard resistors from 10 M $\Omega$  to 1 T $\Omega$  [1]. An extensive comparison of the systems will be reported at the conference along with uncertainty analysis for the automated multimegohm system.

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